

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE JAN 14 2003 LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 03500.017504		APPLICATION NO. 10/647,287	
APPLICANTS mitsutoshi HASEGAWA ET AL.		FILING DATE August 26, 2003		GROUP n/y/a	

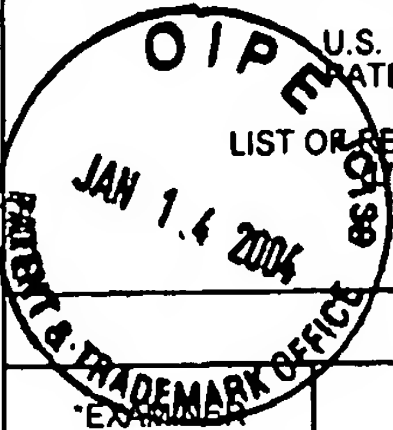
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
KR	6,060,113	05/00	Banno et al.	427	125		
	6,296,896 B1	10/01	Takahashi et al.	427	77		
	2003/0067263 A1	04/03	Tokio et al.	313	493	08/28/02	
	6,624,586 B2	09/03	Abe et al.	315	169.1		
	5,455,597	10/95	Nakamura et al.	345	75		
	5,659,329	08/97	Yamanobe et al.	345	74		
KR	6,137,218	10/00	Kaneko et al.	313	495		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
7-326311	12/95	Japan			Abstract		
8-185818	07/96	Japan			Abstract		
9-50757	02/97	Japan			Abstract		
9-102271	04/97	Japan			Abstract		
2000-251665	9/00	Japan			Abstract		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	M. Hartwell et al, "Strong electron emission from patterned tin-indium oxide thin films", International Electron Devices Meeting 1975, Washington, D.C., Catalog No. 75, CH1023-1, IEDM Technical Digest, pp. 519-521.

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 4/5/05
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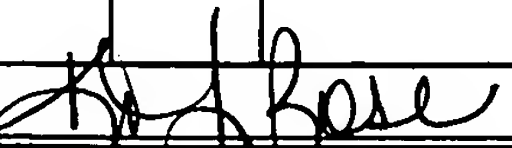
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) <div style="text-align: center;">  </div> U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. 03500.017504		APPLICATION NO. 10/647,287	
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KR		6,254,449 B1	07/01	Nakanishi et al.	445	25	08/98
		6,283,813 B1	09/01	Kaneko et al.	445	24	
		2002/0180342 A1	12/02	Yamada et al.	313	493	07/02
		6,506,089 B2	01/03	Nakanishi et al.	445	25	02/01
KR		2003/0058192 A1	03/03	Arai et al.	345	59	09/02

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	64-31332	2/89	Japan			Abstract
	JP	6-342636	12/94	Japan			Abstract
	JP	11-135018	05/99	Japan			Abstract
	JPP	2001-210258	8/01	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

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